

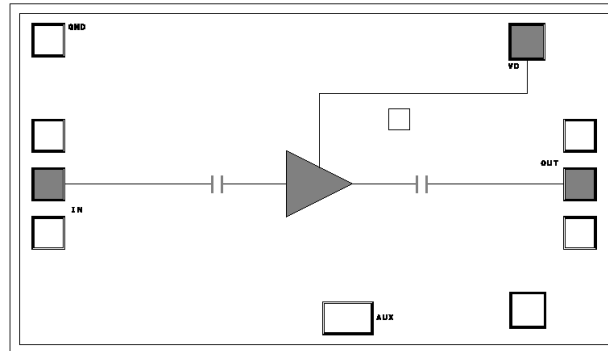
### Features

- Low Noise Amplifier (Single DC Biased)
- Frequency: 18 - 40GHz
- Small Signal Gain:  
19.5dB@18GHz  
19dB@40GHz Typical
- Gain Flatness:  $\pm 1.5$ dB Typical
- Noise Figure: 2.7dB Typical
- P1dB: 15dBm Typical
- Power Supply: +5V/75mA
- Input/Output: 50 $\Omega$
- Chip Size: 1.85 x 1.05 x 0.1mm

### Typical Applications

- Test Instrumentation
- Microwave Radio & VSAT
- Military & Space
- Telecom Infrastructure
- Fiber Optics

### Functional Block Diagram

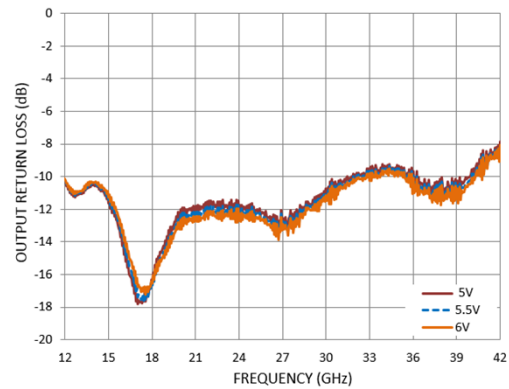
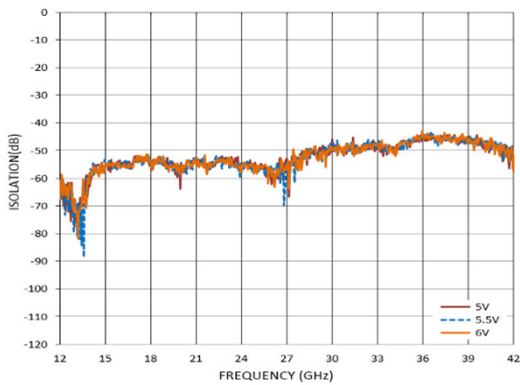
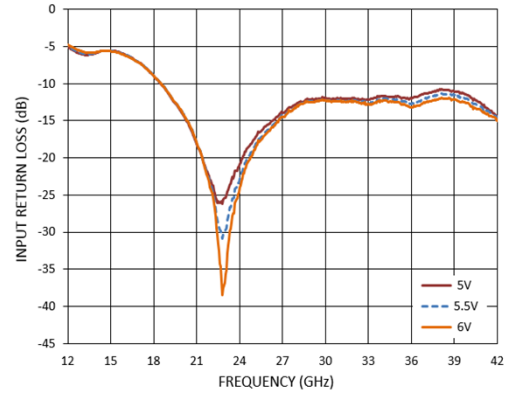
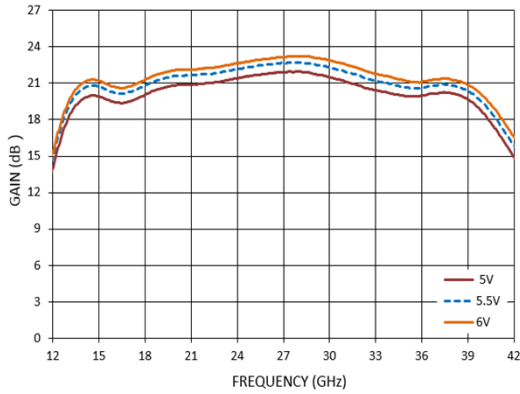


### Electrical Specifications

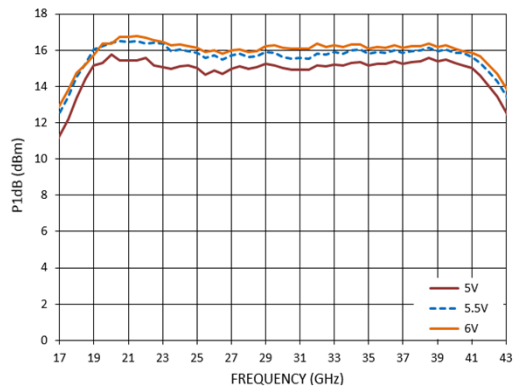
TA = +25°C, VD = 5V, IDD = 75mA Typical

Parameters	Min.	Typ.	Max.	Min.	Typ.	Max.	Units
Frequency	18-30		30-40				GHz
Small Signal Gain		21			20		dB
Gain Flatness		$\pm 1.0$			$\pm 1.0$		dB
Noise Figure		3.1			2.7		dB
P1dB - Output 1dB Compression	12	15		12	15		dBm
Past - Saturated Output Power)		16			16		dBm
OIP3 - Output Third Order Intercept		22			22		dBm
Input Return Loss		15			15		dB
Output Return Loss		12			10		dB

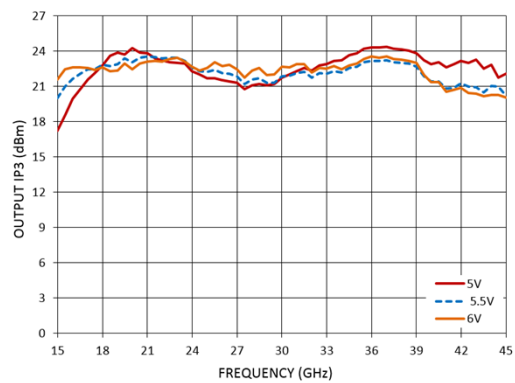
**Measurement Plots: S-parameters**

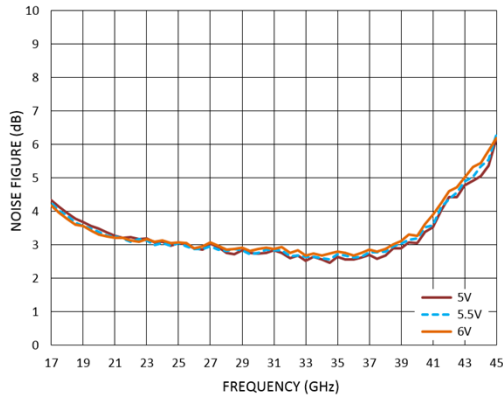


**Measurement Plots: P1dB**



**Measurement Plots: OIP3**



**Measurement Plots: Noise Figure**

**Absolute Maximum Ratings**

Drain Bias Voltage (VD)	+7V
RF Input Power (RFIN)(VD=+5V)	+10 dBm
Channel Temperature	150 °C
Continuous P <sub>diss</sub> (T = 85 °C)(derate 24 mW/°C above 85 °C)	25dBm
Thermal Resistance (channel to die bottom)	50°C/W
Operating Temperature	-55 to +85 °C
Storage Temperature	-55 to +150 °C

**Typical Supply Current vs. V<sub>dd</sub>**

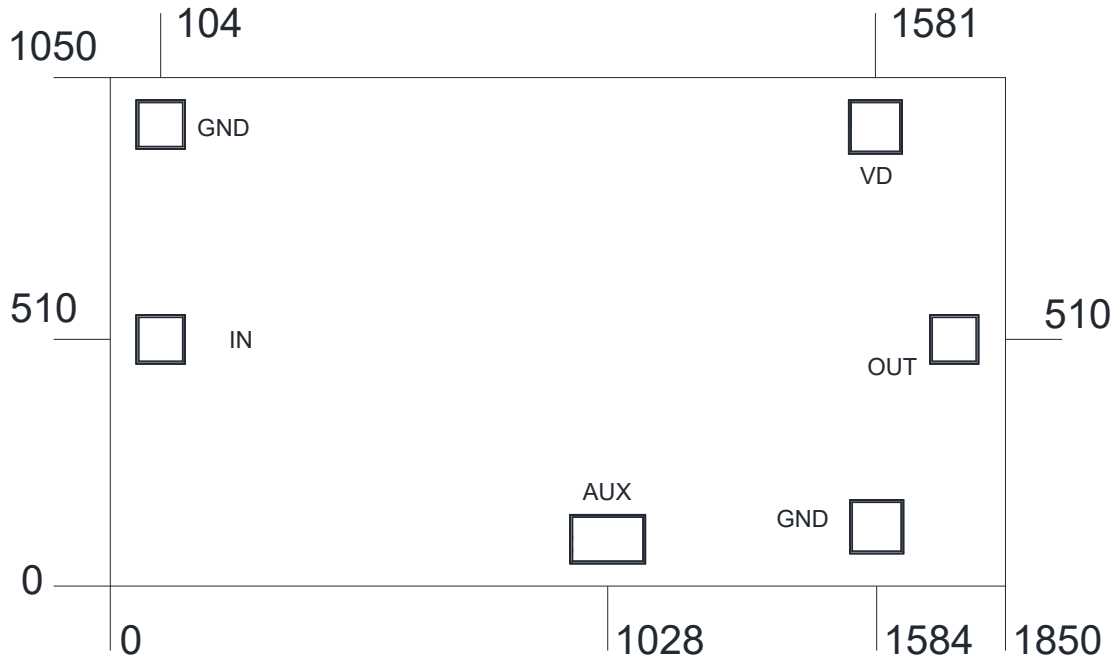
VD (V)	IDD (mA)
+5	75
+5.5	90
+6	105



**ELECTROSTATIC SENSITIVE DEVICE  
OBSERVE HANDLING PRECAUTIONS**



**Outline Drawing:**  
All Dimensions in  $\mu\text{m}$

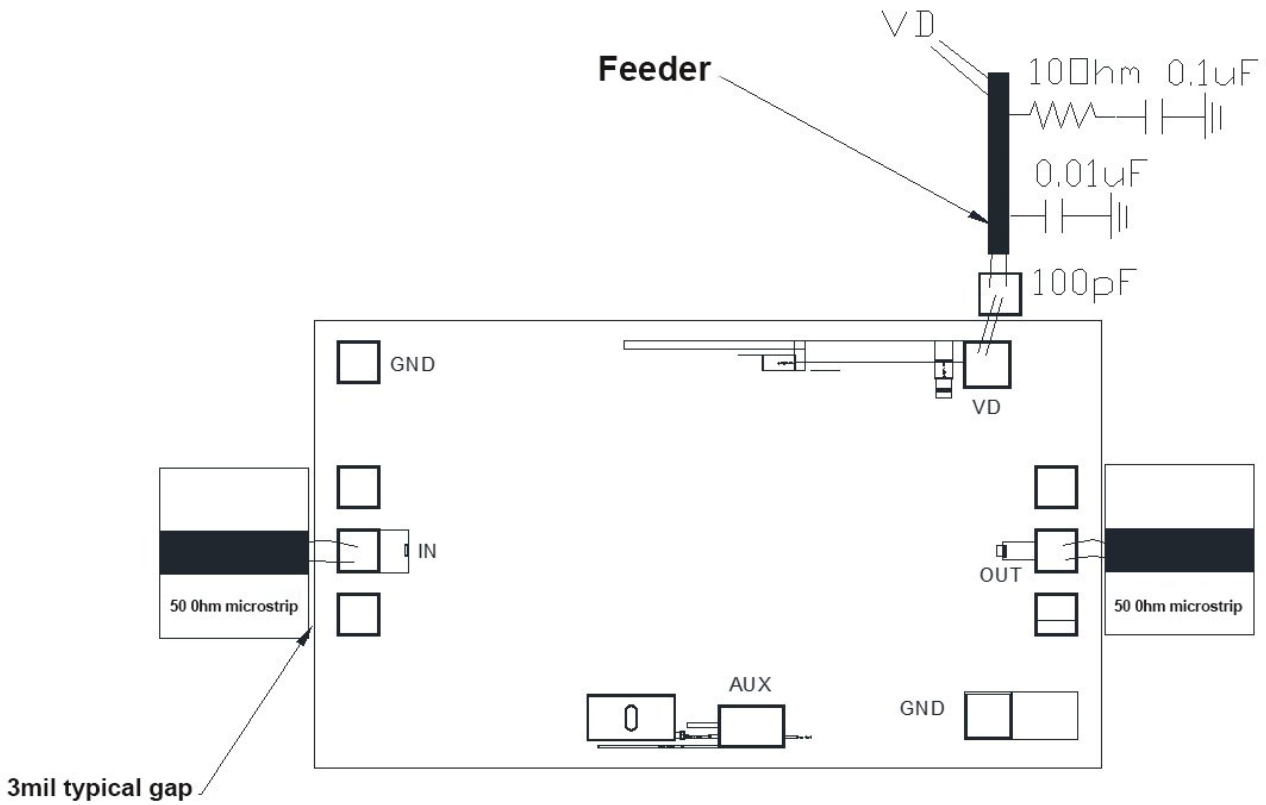


**Notes:**

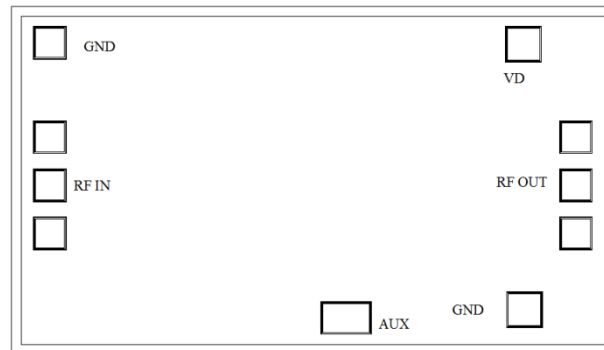
1. Die thickness: 100 $\mu\text{m}$
2. DC bond pad is 100 x 100  $\mu\text{m}^2$
3. RF IN/OUT bond pad is 100 x 100  $\mu\text{m}^2$
4. DC bond pad is 100 x 100  $\mu\text{m}^2$
5. No DC Blocking Capacitor needed for RF input & RF output
6. Bond pad metalization: Gold
7. Backside metalization: Gold
8. Backside of the die (GND)



### Assembly Drawing



No	Function	Description
1	RF IN	Signal input terminal, connected to 50Ω circuit
2	RF OUT	Signal output terminal, connected to 50Ω circuit
3	VD	Connect to external 100pF and 0.01uF bypass capacitors.
9	GND1, GND2	Ground pad.



## Biasing and Operation

Performance is optimized when the drain voltage VD is set to +5 V.

### Turn ON procedure:

1. Connect Input and Output with 50 Ohm source/load.
2. Apply positive drain voltage VD and set to +5V
3. Apply RF signal

### Turn OFF procedure:

1. Turn off RF signal
2. Turn off positive drain voltage VD

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